GigaDevice Semiconductor Inc.

Differences between GD32E51x and GD32E50x products

Application Note AN205

Revision 1.0

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1. Introduction

This application note introduces the characteristic differences between GD32E51x and GD32E50x product series, mainly for electric characteristics and peripheral function characteristics, the differences are described in the following paragraphs. The applicable products are as shown in <u>Table 1-1. GD32E51x and GD32E50x products</u>.

Table 1-1. GD32E51x and GD32E50x products

Part Numbers	Products
	GD32E503xx
	GD32E505xx
GD32E50x	GD32E507xx
	GD32E508xx
	GD32EPRTxx
	GD32E513xx
GD32E51x	GD32E517xx
GD32E51X	GD32E518xx
	GD32EPRTxxA



2. Electric characteristic differences

2.1. DC operating conditions

DC operating conditions differences are reflected in supply voltage, which refers to <u>Table 2-1.</u>
<u>Differences of DC operating conditions</u>.

Table 2-1. Differences of DC operating conditions

Part Numbers	Symbol	Parameter	Conditions	Min ⁽¹⁾	Unit
	V_{DD}	Supply voltage	-	1.71	
GD32E50x	V _{DDA}	Analog supply voltage, f _{ADCMAX} = 14 MHz	-	1.71	
	V _{BAT}	Battery supply voltage	-	1.71 ⁽²⁾	V
	V_{DD}	Supply voltage	-	1.62	V
GD32E51x	V_{DDA}	Analog supply voltage, f _{ADCMAX} = 14 MHz	-	1.62	
	V_{BAT}	Battery supply voltage	-	1.62 ⁽²⁾	

Note:

- (1) Based on characterization, not tested in production.
- (2) In the application which V_{BAT} supply the backup domains, if the VBAT voltage drops below the minimum value, when V_{DD} is powered on again, it is necessary to refresh the registers of backup domains and enable LXTAL again.

2.2. Start-up timings of operating conditions

Start-up timings of operating conditions differences are reflected in the start time when the system clock source is HXTAL or IRC8M, which refers to <u>Table 2-2. Differences of start-up timings of operating conditions</u>.

Table 2-2. Differences of start-up timings of operating conditions

Part Numbers	Symbol	Parameter	Conditions	Тур	Unit
GD32E50x			Clock source from HXTAL	608	
GDUZEUUX	•	Start-up time	Clock source from IRC8M	74	-16
000051	tstart-up	otan ap umo	Clock source from HXTAL	2270	μs
GD32E51x			Clock source from IRC8M	104.8	



Note:

- (1) Based on characterization, not tested in production.
- (2) After power-up, the start-up time is the time between the rising edge of NRST high and the first I/O instruction conversion in SystemInit function.
- (3) PLL is off.

2.3. Power saving mode wakeup timings characteristics

Power saving mode wakeup timings characteristics differences are reflected in wakeup time from Sleep mode, Deep-sleep mode, Deep-sleep mode 1, Deep-sleep mode 2 and standby mode, which refers to <u>Table 2-3</u>. <u>Differences of power saving mode wakeup timings</u>.

Table 2-3. Differences of power saving mode wakeup timings characteristics

Part Numbers	Symbol	Parameter	Тур	Unit
	t _{Sleep}	Wakeup from Sleep mode	1.7	
		Wakeup from Deep-sleep mode (LDO On)	3.1	
		Wakeup from Deep-sleep mode (LDO in low	3.1	
		power mode)	3.1	
GD32E50x	t _{Deep-sleep}	Wakeup from Deep-sleep mode1 (LDO in low	4.3	
		power and low driver mode)	4.3	
		Wakeup from Deep-sleep mode2 (LDO in low	11.7	
		power and low driver mode)	11.7	
	t _{Standby}	Wakeup from Standby mode	77.2	110
	t _{Sleep}	Wakeup from Sleep mode	2.16	μs
		Wakeup from Deep-sleep mode (LDO On)	4.74	
		Wakeup from Deep-sleep mode (LDO in low	4.74	
		power mode)	4.74	
GD32E51x	t _{Deep-sleep}	Wakeup from Deep-sleep mode1 (LDO in low	7.16	
		power and low driver mode)	7.10	
		Wakeup from Deep-sleep mode2 (LDO in low	7.84	
		power and low driver mode)	7.04	
	t _{Standby}	Wakeup from Standby mode	105.2	

Note

- (1) Based on characterization, not tested in production.
- (2) The wakeup time is measured from the wakeup event to the point at which the application code reads the first instruction under the below conditions: $V_{DD} = V_{DDA} = 3.3 \text{ V}$, IRC8M = System clock = 8 MHz.

2.4. Power consumption

The power consumption differences are reflected in supply current in deep-sleep mode and standby mode, which refers to <u>Table 2-4. Differences of power consumption</u> <u>characteristics in deep-sleep mode</u>, <u>Table 2-5. Differences of power consumption</u> <u>characteristics in deep-sleep mode 1</u>, <u>Table 2-6. Differences of power consumption</u> <u>characteristics in deep-sleep mode 2</u> and <u>Table 2-7. Differences of Power consumption</u>



characteristics in standby mode.

Table 2-4. Differences of power consumption characteristics in deep-sleep mode

Part Numbers	Symbo	Parameter	Conditions	Min	Тур	Max	Unit
			V _{DD} = V _{DDA} = 3.3 V, LDO in normal power and normal driver mode, IRC40K off, RTC off, all GPIOs are configured as analog mode	_	461.3 3		μΑ
OD22550v			$V_{DD} = V_{DDA} = 3.3 \text{ V}$, LDO in low power and normal driver mode, IRC40K off, RTC off, all GPIOs are configured as analog mode	_	413.0 0		μА
GD32E30X	032E50x		V _{DD} = V _{DDA} = 3.3 V, LDO in normal power and low driver mode, IRC40K off, RTC off, all GPIOs are configured as analog mode	_	258.0 0		μΑ
		Supply current	V _{DD} = V _{DDA} = 3.3 V, LDO in low power and low driver mode, IRC40K off, RTC off, all GPIOs are configured as analog mode	_	210.6 7		μΑ
	I _{DD} +I _{DDA}	(Deep-Sleep mode)	V _{DD} = V _{DDA} = 3.3 V, LDO in normal power and normal driver mode, IRC40K off, RTC off, all GPIOs are configured as analog mode		146.4 7		μΑ
GD32E51x			V _{DD} = V _{DDA} = 3.3 V, LDO in low power and normal driver mode, IRC40K off, RTC off, all GPIOs are configured as analog mode		96.70	ı	μΑ
GD32E31X			V _{DD} = V _{DDA} = 3.3 V, LDO in normal power and low driver mode, IRC40K off, RTC off, all GPIOs are configured as analog mode	_	106.6 7		μΑ
			V _{DD} = V _{DDA} = 3.3 V, LDO in low power and low driver mode, IRC40K off, RTC off, all GPIOs are configured as analog mode	_	59.20		μΑ

Table 2-5. Differences of power consumption characteristics in deep-sleep mode 1

Part Numbers	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
GD32E50x	I _{DD} +I _{DDA}	Supply current	$V_{DD} = V_{DDA} = 3.3 \text{ V, LDO in low}$	_	163.3	_	μΑ



Part Numbers	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		(Deep-Sleep 1	power and low driver mode,		3		
GD32E51x		mode)	IRC40K off, RTC off, all GPIOs		48.30		uА
GD3ZE31X			are configured as analog mode		40.30		μΑ

Table 2-6. Differences of power consumption characteristics in deep-sleep mode 2

Part Numbers	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
GD32E50x	l l	Supply current	$V_{DD} = V_{DDA} = 3.3 \text{ V, LDO in low}$ power and low driver mode,	_	68.0 0	_	μA
GD32E51x	IDD+IDDA	(Deep-Sleep 2 mode)	IRC40K off, RTC off, all GPIOs are configured as analog mode	_	30.0 4	_	μA

Table 2-7. Differences of Power consumption characteristics in standby mode

Part Numbers	Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
			$V_{DD} = V_{DDA} = 3.3 \text{ V, LXTAL off,}$		3.79			
			IRC40K on, RTC on		3.19			
GD32E50x			$V_{DD} = V_{DDA} = 3.3 \text{ V, LXTAL off,}$		3.58			
GD32E30X			IRC40K on, RTC off		3.56		μA	
	laa 1 laa 1	Supply current IRC40K off, RTC off	$V_{DD} = V_{DDA} = 3.3 \text{ V, LXTAL off,}$		3.08			
			Supply current	IRC40K off, RTC off		5.00		
	I _{DD} +I _{DDA}	(Standby mode)	$V_{DD} = V_{DDA} = 3.3 \text{ V, LXTAL off,}$		3.07			
					IRC40K on, RTC on		3.07	
GD32E51x			$V_{DD} = V_{DDA} = 3.3 \text{ V, LXTAL off,}$		2.82			
GD32E31X			IRC40K on, RTC off		2.02		μA	
			$V_{DD} = V_{DDA} = 3.3 \text{ V, LXTAL off,}$		2.06			
			IRC40K off, RTC off		2.00			

Note: Based on characterization, not tested in production.

2.5. Electrostatic discharges (ESD)

The ESD difference refers to <u>Table 2-8. Differences of ESD level</u>.



Table 2-8. Differences of ESD level

Part Numbers	Symbol Parameter		Conditions	Min	Тур	Max	Unit
CD22F60v	V _{ESD(HBM)}	Electrostatic discharge voltage (human body model)	$T_A=25$ °C; ESDA/JEDEC JS- 001-2017	_	6000		
GD32E50x	V _{ESD(CDM)}	Electrostatic discharge voltage (charge device model)	T _A =25 °C; ESDA/JEDEC JS- 002-2018	_	1000		V
GD32E51x	V _{ESD(HBM)}	Electrostatic discharge voltage (human body model)	T _A =25 °C; ESDA/JEDEC JS- 001-2017	_	5000	_	V
GD32E31X	V _{ESD(CDM)}	Electrostatic discharge voltage (charge device model)	T_A =25 °C; ESDA/JEDEC JS- 002-2018	_	500		

Note:

2.6. External clock

The external clock difference is reflected in LXTAL startup time, which refers to <u>Table 2-9.</u> <u>Differences of LXTAL startup time</u>.

Table 2-9. Differences of LXTAL startup time

Part Numbers	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
GD32E50x	tsulxtal ⁽¹⁾⁽²⁾		_		2		
GD32E51x		Crystal or ceramic startup time		_	0.6	_	S

Note:

- (1) Based on characterization, not tested in production.
- (2) t_{SULXTAL} is the startup time measured from the moment it is enabled (by software) to the 32.768 kHz oscillator stabilization flags is SET. This value varies significantly with the crystal manufacturer.

2.7. Internal clock

The internal clock differences are reflected in IRC40K and IRC48M startup time, which refers to <u>Table 2-10. Differences of IRC40K startup time</u> and <u>Table 2-11. Differences of IRC48M</u> <u>startup time</u>.

Table 2-10. Differences of IRC40K startup time

Part Numbers	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
GD32E50x	tsuirc40K	IRC40K oscillator startup time	V _{DD} = 3.3 V	_	80	_	μs

⁽¹⁾ Based on characterization, not tested in production.



GD32E51x						1.3			
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Note: Based on characterization, not tested in production.

Table 2-11. Differences of IRC48M startup time

Part Numbers	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
GD32E50x	4	IDC49M assillator startus tima	$V_{DD} = V_{DDA} = 3.3 \text{ V},$		3.68		
GD32E51x	LSUIRC48M	IRC48M oscillator startup time	$f_{HCLK} = f_{HXTAL_PLL} = 180$ MHz		1.3	_	μs

Note: Based on characterization, not tested in production.

2.8. Flash memory

The flash memory characteristics differences are reflected in word programming, page erasing and mass erasing time, which refers to <u>Table 2-12. Differences of flash operating time</u>.

Table 2-12. Differences of flash operating time

	officerices of flash operating time						
Part Numbers	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	PE _{CYC}	Number of guaranteed program / erase cycles before failure (Endurance)		10	_		kcycles
GD32E50x	t _{PROG}	Word programming time			37.5		μs
	terase	Page erase time			11		ms
	t _{MERASE}	Mass erase time	T _A = -40 °C ~		12		ms
	PE _{CYC}	Number of guaranteed program / erase cycles before failure (Endurance)	+85 °C	100	_		kcycles
GD32E51x	t _{PROG}	Word programming time		_	20		μs
	terase	Page erase time		1	_	20	ms
	tmerase	Mass erase time		_	20		ms

 $\textbf{Note:} \ \ \textbf{Guaranteed by design, not tested in production.}$

2.9. Temperature sensor characteristics

The temperature sensor difference is reflected in voltage value at 25℃, which refers to <u>Table</u>



2-13. Differences of temperature sensor characteristics.

Table 2-13. Differences of temperature sensor characteristics

Part Numbers	Symbol	Parameter	Min	Тур	Max	Unit
GD32E50x	V ₂₅	Voltage at 25 °C	_	1.45		V
GD32E51x			_	1.43	_	V

Note: Based on characterization, not tested in production.

2.10. Analog-to-digital converter (ADC)

The ADC characteristics differences are reflected in operating voltage and positive reference voltage, which refers to *Table 2-14. Electric characteristic differences of ADC*.

Table 2-14. Electric characteristic differences of ADC

Part Numbers	Symbol Parameter		Conditions	Min	Тур	Max	Unit
GD32E50x	$V_{DDA}^{(1)}$	Operating voltage		1.71	3.3	3.63	>
GD32E50X	V _{REFP} ⁽²⁾	Positive reference voltage		1.71	_	V_{DDA}	>
GD32E51x	V _{DDA} ⁽¹⁾	Operating voltage	_	1.62	3.3	3.63	٧
GD32E31X	V _{REFP} ⁽²⁾	Positive reference voltage	_	1.62	_	V_{DDA}	٧

Note:

- (1) Based on characterization, not tested in production.
- (2) Guaranteed by design, not tested in production.



3. Peripheral function differences

3.1. Flash memory controller (FMC)

The FMC differences are reflected in the programming width and Flash ECC function, which refers to *Table 3-1. Differences of* .

Table 3-1. Differences of FMC function

Part Numbers	Programming width	Flash ECC check
GD32E50x	32 bit	Not supported
GD32E51x	64 bit	Supported



4. Other differences

4.1. Number of peripherals

Number of peripherals difference refers to <u>Table 4-1. Differences of number of peripherals</u>.

Table 4-1. Differences of number of peripherals

Part Numbers	DAC	TIMER
GD32E50x	DAC	TIMER0/1/2/3/4/5/6/7/8/9/10/11/12/13
GD32E51x	DAC0/1	TIMER0/1/2/3/4/5/6/7/8/9/10/11/12/13/14/15/16



5. Revision history

Table 5-1. Revision history

Revision No.	Description	Date
1.0	Initial Release	Jun.25, 2024



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